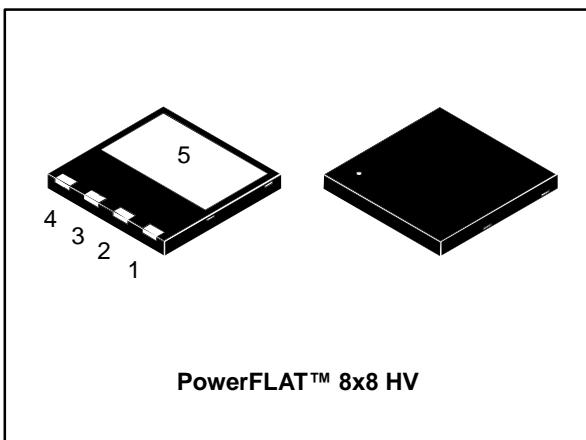
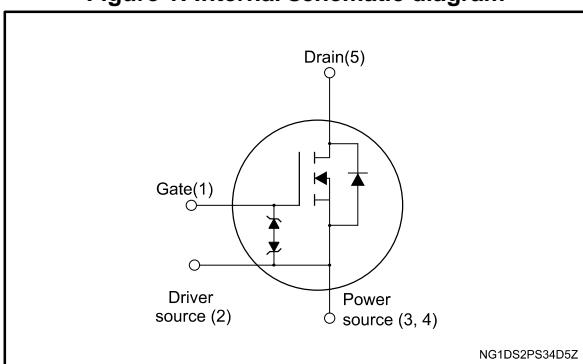


## N-channel 600 V, 0.195 Ω typ., 15 A MDmesh™ DM2 Power MOSFET in a PowerFLAT™ 8x8 HV package

Datasheet - production data



**Figure 1: Internal schematic diagram**



### Features

Order code	V <sub>DS</sub> @ T <sub>Jmax</sub>	R <sub>DS(on)</sub> max.	I <sub>D</sub>
STL24N60DM2	650 V	0.220 Ω	15 A

- Fast-recovery body diode
- Extremely low gate charge and input capacitance
- Low on-resistance
- 100% avalanche tested
- Extremely high dv/dt ruggedness
- Zener-protected

### Applications

- Switching applications

### Description

This high voltage N-channel Power MOSFET is part of the MDmesh™ DM2 fast recovery diode series. It offers very low recovery charge ( $Q_{rr}$ ) and time ( $t_{rr}$ ) combined with low  $R_{DS(on)}$ , rendering it suitable for the most demanding high efficiency converters and ideal for bridge topologies and ZVS phase-shift converters.

**Table 1: Device summary**

Order code	Marking	Package	Packing
STL24N60DM2	24N60DM2	PowerFLAT™ 8x8 HV	Tape and reel

**Contents**

<b>1</b>	<b>Electrical ratings .....</b>	<b>3</b>
<b>2</b>	<b>Electrical characteristics .....</b>	<b>4</b>
2.1	Electrical characteristics (curves).....	6
<b>3</b>	<b>Test circuits .....</b>	<b>8</b>
<b>4</b>	<b>Package information .....</b>	<b>9</b>
4.1	PowerFLAT8x8 HV package information .....	10
4.2	PowerFLAT8x8 HV packaging information .....	12
<b>5</b>	<b>Revision history .....</b>	<b>14</b>

# 1 Electrical ratings

**Table 2: Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{GS}$	Gate-source voltage	$\pm 25$	V
$I_D^{(1)}$	Drain current (continuous) at $T_{case} = 25^\circ C$	15	A
	Drain current (continuous) at $T_{case} = 100^\circ C$	9.5	
$I_{DM}^{(1)(2)}$	Drain current (pulsed)	60	A
$P_{TOT}^{(1)}$	Total dissipation at $T_{case} = 25^\circ C$	125	W
$dv/dt^{(3)}$	Peak diode recovery voltage slope	40	V/ns
$dv/dt^{(4)}$	MOSFET $dv/dt$ ruggedness	50	
$T_{stg}$	Storage temperature range	-55 to 150	$^\circ C$
$T_j$	Operating junction temperature range		

**Notes:**

(1)The value is limited by package

(2)Pulse width limited by safe operating area.

(3) $|I_{SD}| \leq 15 A$ ,  $|di/dt| \leq 400 A/\mu s$ ,  $V_{DS}(\text{peak}) < V_{(BR)DSS}$ ,  $V_{DD}=400 V$ (4)  $V_{DS} \leq 480 V$ .**Table 3: Thermal data**

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case	1	$^\circ C/W$
$R_{thj-pcb}^{(1)}$	Thermal resistance junction-pcb	45	

**Notes:**(1)When mounted on FR-4 board of inch<sup>2</sup>, 2oz Cu.**Table 4: Avalanche characteristics**

Symbol	Parameter	Value	Unit
$I_{AR}$	Avalanche current, repetitive or not repetitive (pulse width limited by $T_{jmax}$ )	3	A
$E_{AS}$	Single pulse avalanche energy (starting $T_j = 25^\circ C$ , $I_D = I_{AR}$ , $V_{DD} = 50 V$ )	160	mJ

## 2 Electrical characteristics

( $T_{case} = 25^\circ C$  unless otherwise specified)

**Table 5: On/off-state**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0 V, I_D = 1 mA$	600			V
$I_{DSS}$	Zero gate voltage drain current	$V_{GS} = 0 V, V_{DS} = 600 V$			1.5	$\mu A$
		$V_{GS} = 0 V, V_{DS} = 600 V, T_{case} = 125^\circ C$			100	
$I_{GSS}$	Gate-body leakage current	$V_{DS} = 0 V, V_{GS} = \pm 25 V$			$\pm 10$	$\mu A$
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	3	4	5	V
$R_{DS(on)}$	Static drain-source on-resistance	$V_{GS} = 10 V, I_D = 9 A$		0.195	0.220	$\Omega$

**Table 6: Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input capacitance	$V_{DS} = 100 V, f = 1 MHz, V_{GS} = 0 V$	-	1055	-	$pF$
$C_{oss}$	Output capacitance		-	56	-	
$C_{rss}$	Reverse transfer capacitance		-	2.4	-	
$C_{oss\ eq.\ (1)}$	Equivalent output capacitance	$V_{DS} = 0$ to $480 V, V_{GS} = 0 V$	-	259	-	$pF$
$R_G$	Intrinsic gate resistance	$f = 1 MHz, I_D = 0 A$	-	7	-	$\Omega$
$Q_g$	Total gate charge	$V_{DD} = 480 V, I_D = 18 A, V_{GS} = 10 V$ (see <a href="#">Figure 15: "Gate charge test circuit"</a> )	-	29	-	$nC$
$Q_{gs}$	Gate-source charge		-	6	-	
$Q_{gd}$	Gate-drain charge		-	12	-	

### Notes:

<sup>(1)</sup>  $C_{oss\ eq.}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ .

**Table 7: Switching times**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 300 V, I_D = 9 A, R_G = 4.7 \Omega, V_{GS} = 10 V$ (see <a href="#">Figure 14: "Switching times test circuit for resistive load"</a> and <a href="#">Figure 19: "Switching time waveform"</a> )	-	15	-	$ns$
$t_r$	Rise time		-	8.7	-	
$t_{d(off)}$	Turn-off delay time		-	60	-	
$t_f$	Fall time		-	15	-	

Table 8: Source-drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}^{(1)}$	Source-drain current		-		15	A
$I_{SDM}^{(2)}$	Source-drain current (pulsed)		-		60	A
$V_{SD}^{(3)}$	Forward on voltage	$V_{GS} = 0 \text{ V}$ , $I_{SD} = 18 \text{ A}$	-		1.6	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 18 \text{ A}$ , $dI/dt = 100 \text{ A}/\mu\text{s}$ , $V_{DD} = 60 \text{ V}$ (see <i>Figure 16: "Test circuit for inductive load switching and diode recovery times"</i> )	-	155		ns
$Q_{rr}$	Reverse recovery charge		-	956		nC
$I_{RRM}$	Reverse recovery current		-	12.5		A
$t_{rr}$	Reverse recovery time	$I_{SD} = 18 \text{ A}$ , $dI/dt = 100 \text{ A}/\mu\text{s}$ , $V_{DD} = 60 \text{ V}$ , $T_j = 150 \text{ }^\circ\text{C}$ (see <i>Figure 16: "Test circuit for inductive load switching and diode recovery times"</i> )	-	200		ns
$Q_{rr}$	Reverse recovery charge		-	1450		nC
$I_{RRM}$	Reverse recovery current		-	13		A

**Notes:**

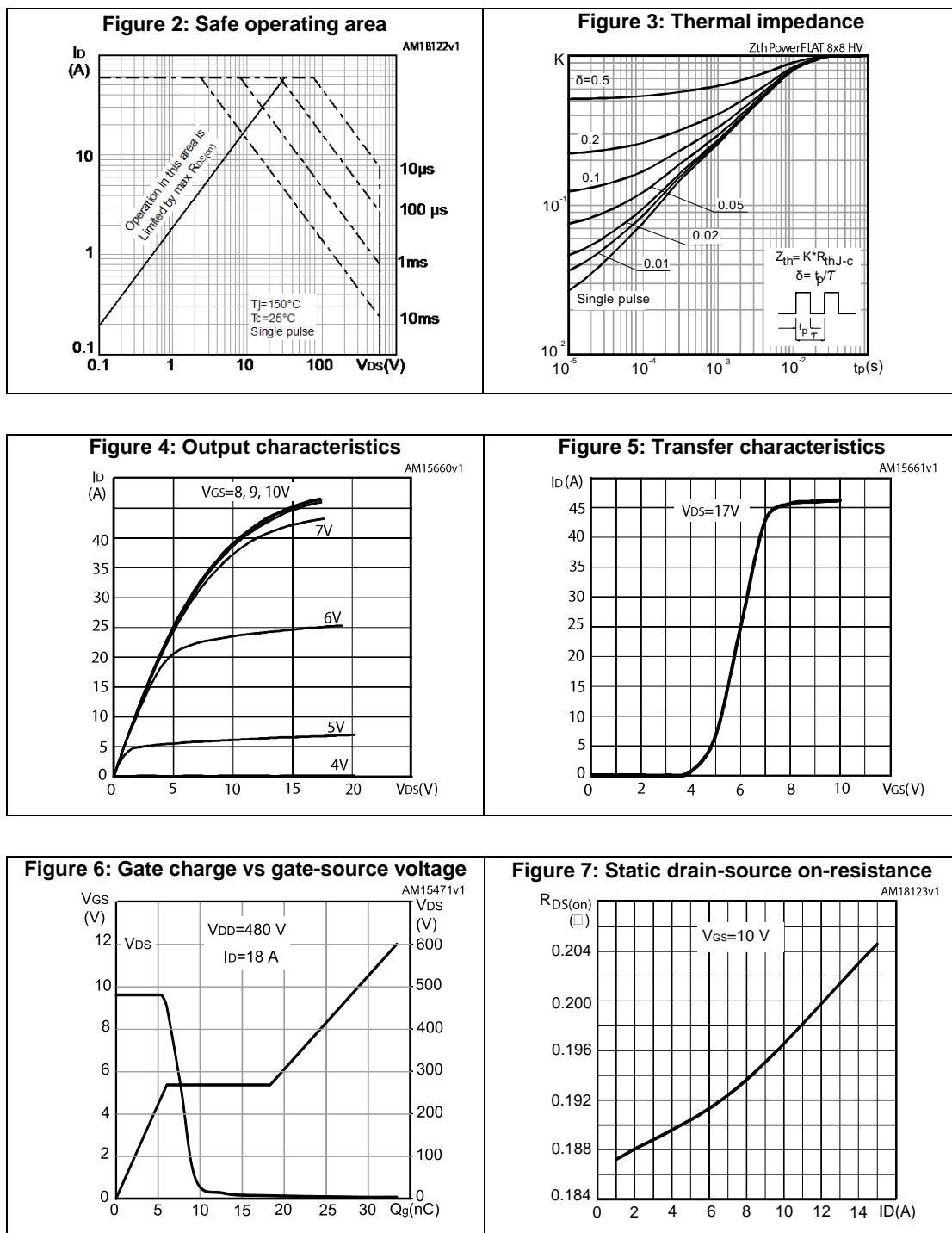
(1)The value is limited by package.

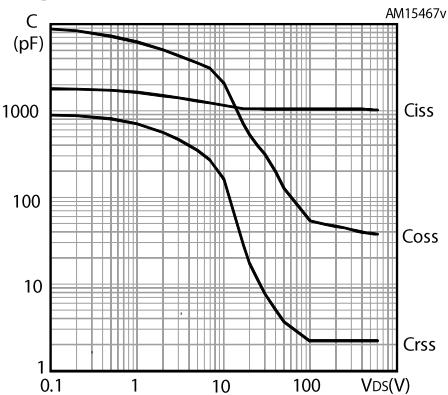
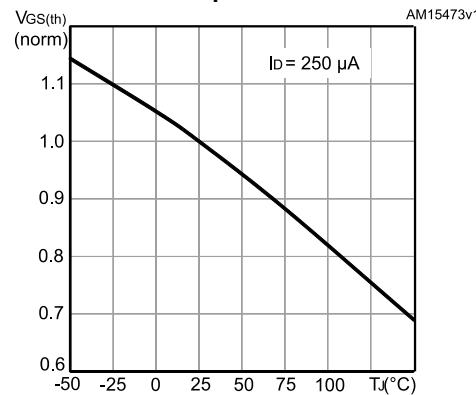
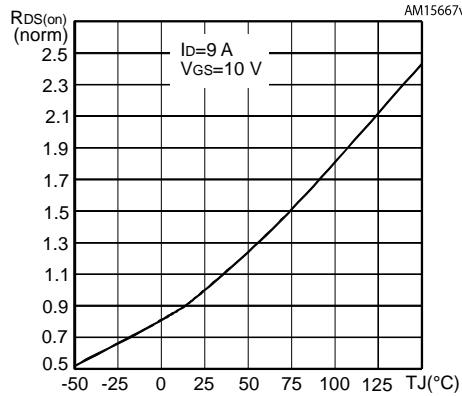
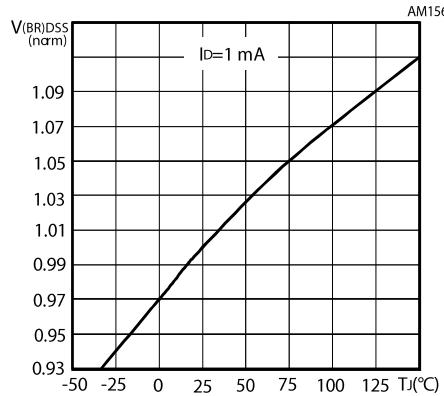
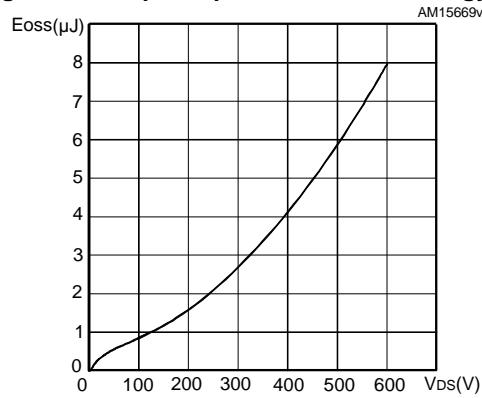
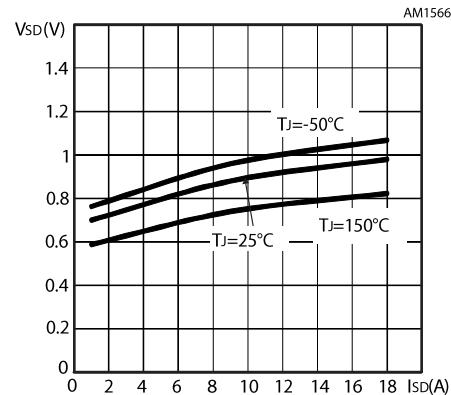
(2)Pulse width limited by safe operating area

(3) Pulsed: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%

## 2.1

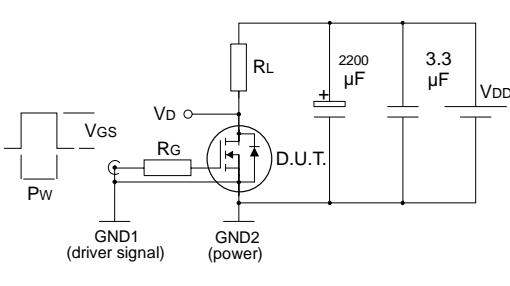
## Electrical characteristics (curves)



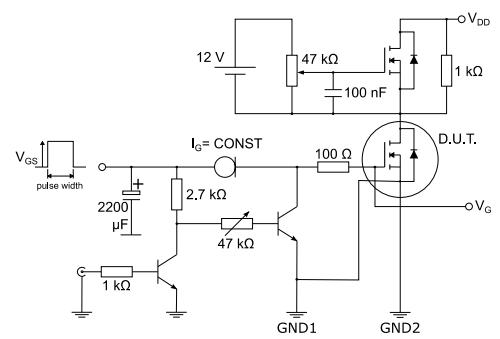
**Figure 8: Capacitance variations****Figure 9: Normalized gate threshold voltage vs temperature****Figure 10: Normalized on-resistance vs temperature****Figure 11: Normalized V(BR)DSS vs temperature****Figure 12: Output capacitance stored energy****Figure 13: Source- drain diode forward characteristics**

### 3 Test circuits

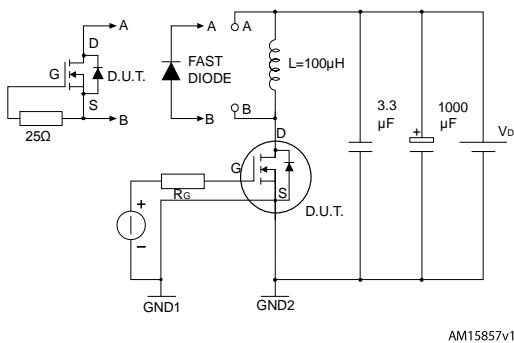
**Figure 14: Switching times test circuit for resistive load**



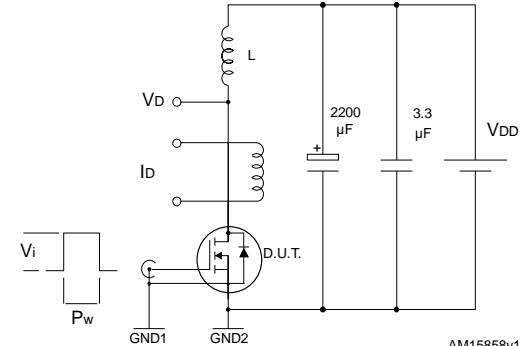
**Figure 15: Gate charge test circuit**



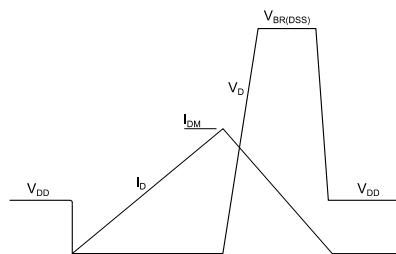
**Figure 16: Test circuit for inductive load switching and diode recovery times**



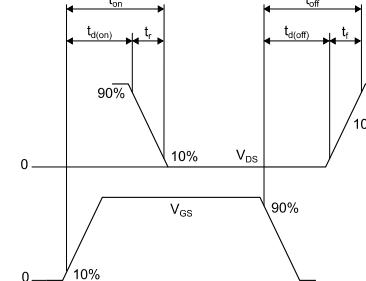
**Figure 17: Unclamped inductive load test circuit**



**Figure 18: Unclamped inductive waveform**



**Figure 19: Switching time waveform**

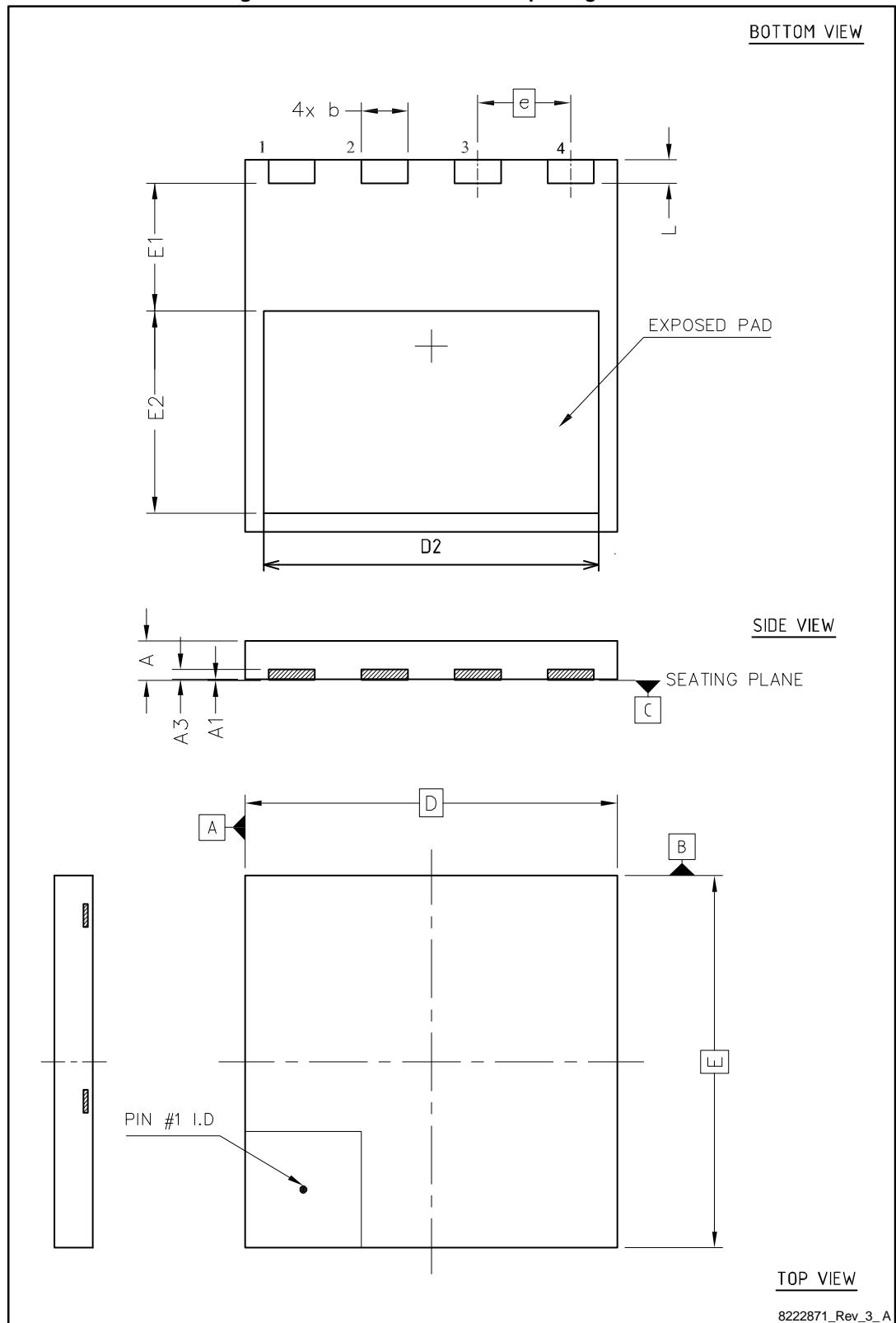


## 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com).  
ECOPACK® is an ST trademark.

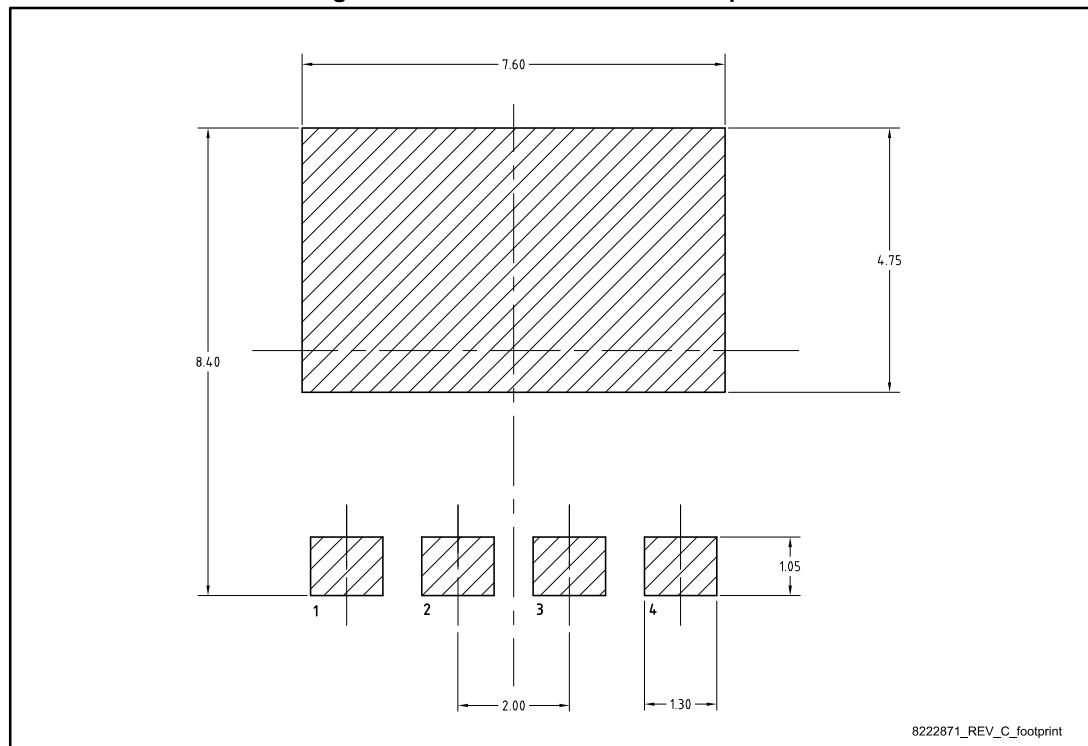
## 4.1 PowerFLAT8x8 HV package information

Figure 20: PowerFLAT™ 8x8 HV package outline



**Table 9: PowerFLAT™ 8x8 HV mechanical data**

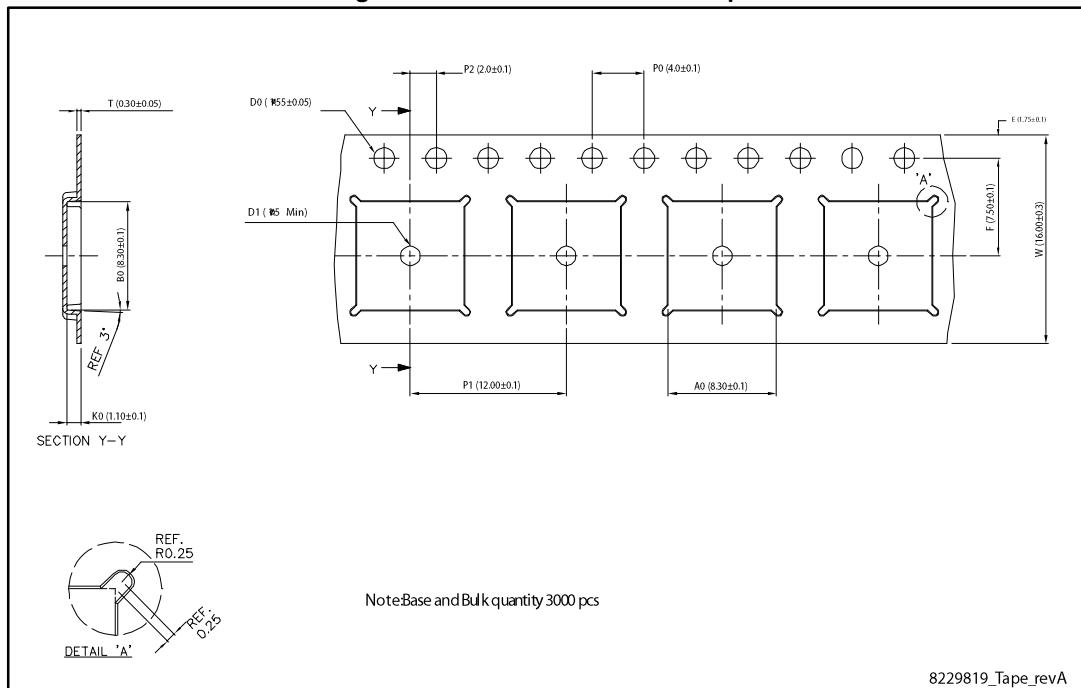
Dim.	mm		
	Min.	Typ.	Max.
A	0.75	0.85	0.95
A1	0.00		0.05
A3	0.10	0.20	0.30
b	0.90	1.00	1.10
D	7.90	8.00	8.10
E	7.90	8.00	8.10
D2	7.10	7.20	7.30
E1	2.65	2.75	2.85
E2	4.25	4.35	4.45
e		2.00	
L	0.40	0.50	0.60

**Figure 21: PowerFLAT™ 8x8 HV footprint**

All dimensions are in millimeters.

## 4.2 PowerFLAT™ 8x8 HV packaging information

Figure 22: PowerFLAT™ 8x8 HV tape



All dimensions are in millimeters.

Figure 23: PowerFLAT™ 8x8 HV package orientation in carrier tape

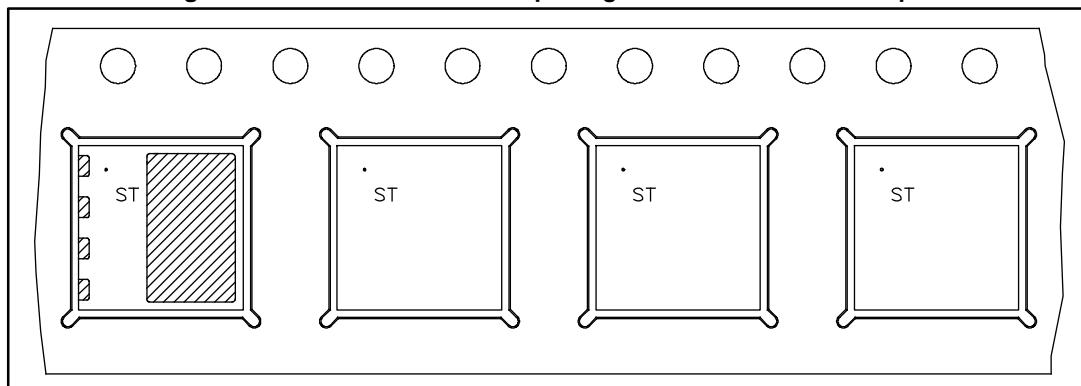
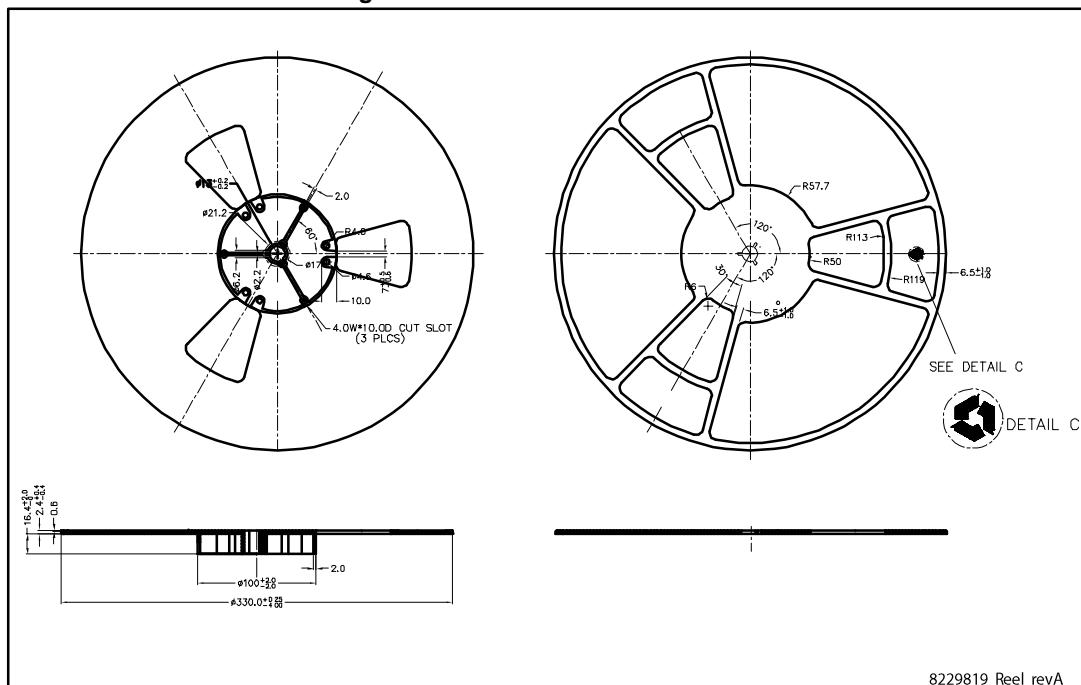


Figure 24: PowerFLAT™ 8x8 HV reel



All dimensions are in millimeters.

## 5 Revision history

Table 10: Document revision history

Date	Revision	Changes
03-Mar-2014	1	First release.
21-Jan-2016	2	Modified: title, features, description and internal schematic in cover page Modified: <i>Section 3: "Test circuits"</i> Updated: <i>Section 4: "Package information"</i> Minor text changes
25-Jul-2016	3	Document status promoted from preliminary to production data.

**IMPORTANT NOTICE – PLEASE READ CAREFULLY**

STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, enhancements, modifications, and improvements to ST products and/or to this document at any time without notice. Purchasers should obtain the latest relevant information on ST products before placing orders. ST products are sold pursuant to ST's terms and conditions of sale in place at the time of order acknowledgement.

Purchasers are solely responsible for the choice, selection, and use of ST products and ST assumes no liability for application assistance or the design of Purchasers' products.

No license, express or implied, to any intellectual property right is granted by ST herein.

Resale of ST products with provisions different from the information set forth herein shall void any warranty granted by ST for such product.

ST and the ST logo are trademarks of ST. All other product or service names are the property of their respective owners.

Information in this document supersedes and replaces information previously supplied in any prior versions of this document.

© 2016 STMicroelectronics – All rights reserved